

Application/Control	No
10/573 823	

Examiner Hai H. Huynh Applicant(s)/Patent under Reexamination

ITO, YASUSHI

Art Unit 3747

				ISSUE	<u>UL</u>	<u>.A3</u>	SIF		-						
		ORIGINAL	INTERNATIONAL CLASSIFICATION												
CLASS SUBCL				ASS	AIMED				NON-CLAIMED						
123 43			1	F	02	В	7	/00	F	02	D	41	/06		
	CROS	S REFERENCE	ES						,					,	
CLASS	SUBCLA	SS (ONE SUBC	CLASS PE	R BLOCK)										,	
123	491								1					1	
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(Assistant Examiner) (Date)						Huyi	- nh R	/20/20	Total Claims Allowed: 6						
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1	1			31			61			91			121			151			181
2	2			32		•	62			92			122			152			182
3	3			33			63			93			123			153			183
	4			34			64			94			124			154			184
4	3			35			65			95			125			155			185
5	6			36			66			96			126			156			186
6	7			37			67			97			127			157			187
	$\Big)_{\infty}$			38			68			98			128			158			188
	9			39			69			99			129			159			189
	10			40			70			100			130			160			190
	11			41			71			101			131			161			191
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	15			45			75			105			135			165			195
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	17			47			77			107			137			167			197
	18			48			78			108			138			168			198
	19			49			79			109			139			169			199
	20			50			80			110			140			170			200
	21			51			81			111			141			171			201
	22			52			82			112			142			172			202
	23			53			83			113]		143			173			203
	24			54			84			114			144			174			204
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	26			56			86			116			146			176			206
	27]		57			87			117			147			177			207
	28]		58			88			118			148			178			208
	29			59			89			119			149			179			209
	30		<u> </u>	60		<u> </u>	90			120			150			180			210